

54AC08 Quad 2-Input AND Gate

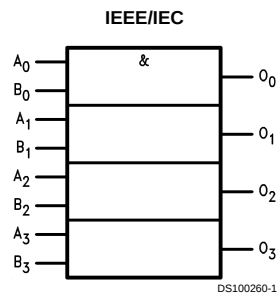
General Description

The 'AC08 contains four, 2-input AND gates.

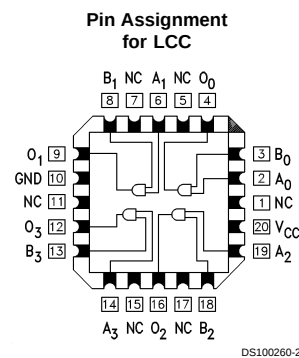
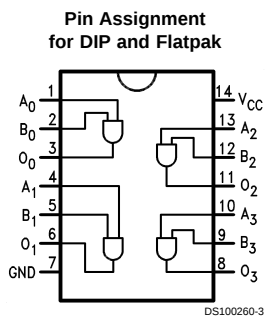
Features

- I_{CC} reduced by 50%
- Outputs source/sink 24 mA
- Standard Microcircuit Drawing (SMD) 5962-87615
- For Military 54ACT08 device, see 54ACTQ08

Logic Symbols



Connection Diagrams



Pin Names	Description
A_n, B_n	Inputs
O_n	Outputs

Absolute Maximum Ratings (Note 1)

If Military/Aerospace specified devices are required, please contact the National Semiconductor Sales Office/ Distributors for availability and specifications.

Supply Voltage (V_{CC})	-0.5V to +7.0V
DC Input Diode Current (I_{IK})	
$V_I = -0.5V$	-20 mA
$V_I = V_{CC} + 0.5V$	+20 mA
DC Input Voltage (V_I)	-0.5V to $V_{CC} + 0.5V$
DC Output Diode Current (I_{OK})	
$V_O = -0.5V$	-20 mA
$V_O = V_{CC} + 0.5V$	+20 mA
DC Output Voltage (V_O)	-0.5V to $V_{CC} + 0.5V$
DC Output Source or Sink Current (I_O)	± 50 mA
DC V_{CC} or Ground Current per Output Pin (I_{CC} or I_{GND})	± 50 mA
Storage Temperature (T_{STG})	-65°C to +150°C
Junction Temperature (T_J)	
CDIP	175°C

Recommended Operating Conditions

Supply Voltage (V_{CC})	
'AC	2.0V to 6.0V
Input Voltage (V_I)	0V to V_{CC}
Output Voltage (V_O)	0V to V_{CC}
Operating Temperature (T_A)	
54AC	-55°C to +125°C
Minimum Input Edge Rate ($\Delta V/\Delta t$)	
'AC Devices	
V_{IN} from 30% to 70% of V_{CC}	
V_{CC} @ 3.3V, 4.5V, 5.5V	125 mV/ns

Note 1: Absolute maximum ratings are those values beyond which damage to the device may occur. The databook specifications should be met, without exception, to ensure that the system design is reliable over its power supply, temperature, and output/input loading variables. National does not recommend operation of FACT™ circuits outside databook specifications.

DC Characteristics for 'AC Family Devices

Symbol	Parameter	V_{CC} (V)	54AC	Units	Conditions
			$T_A = -55^\circ\text{C to } +125^\circ\text{C}$		
			Guaranteed Limits		
V_{IH}	Minimum High Level Input Voltage	3.0	2.1	V	$V_{OUT} = 0.1V$ or $V_{CC} - 0.1V$
		4.5	3.15		
		5.5	3.85		
V_{IL}	Maximum Low Level Input Voltage	3.0	0.9	V	$V_{OUT} = 0.1V$ or $V_{CC} - 0.1V$
		4.5	1.35		
		5.5	1.65		
V_{OH}	Minimum High Level Output Voltage	3.0	2.9	V	$I_{OUT} = -50 \mu A$
		4.5	4.4		
		5.5	5.4		
		3.0	2.4	V	(Note 2) $V_{IN} = V_{IL}$ or V_{IH} -12 mA I_{OH} -24 mA -24 mA
		4.5	3.7		
		5.5	4.7		
V_{OL}	Maximum Low Level Output Voltage	3.0	0.1	V	$I_{OUT} = 50 \mu A$
		4.5	0.1		
		5.5	0.1		
		3.0	0.5	V	(Note 2) $V_{IN} = V_{IL}$ or V_{IH} 12 mA I_{OL} 24 mA 24 mA
		4.5	0.5		
		5.5	0.5		
I_{IN}	Maximum Input Leakage Current	5.5	± 1.0	μA	$V_I = V_{CC}$, GND
I_{OLD}	(Note 3) Minimum Dynamic Output Current	5.5	50	mA	$V_{OLD} = 1.65V$ Max
I_{OHD}		5.5	-50	mA	$V_{OHD} = 3.85V$ Min
I_{CC}	Maximum Quiescent Supply Current	5.5	40.0	μA	$V_{IN} = V_{CC}$ or GND

Note 2: All outputs loaded; thresholds on input associated with output under test.

Note 3: Maximum test duration 2.0 ms, one output loaded at a time.

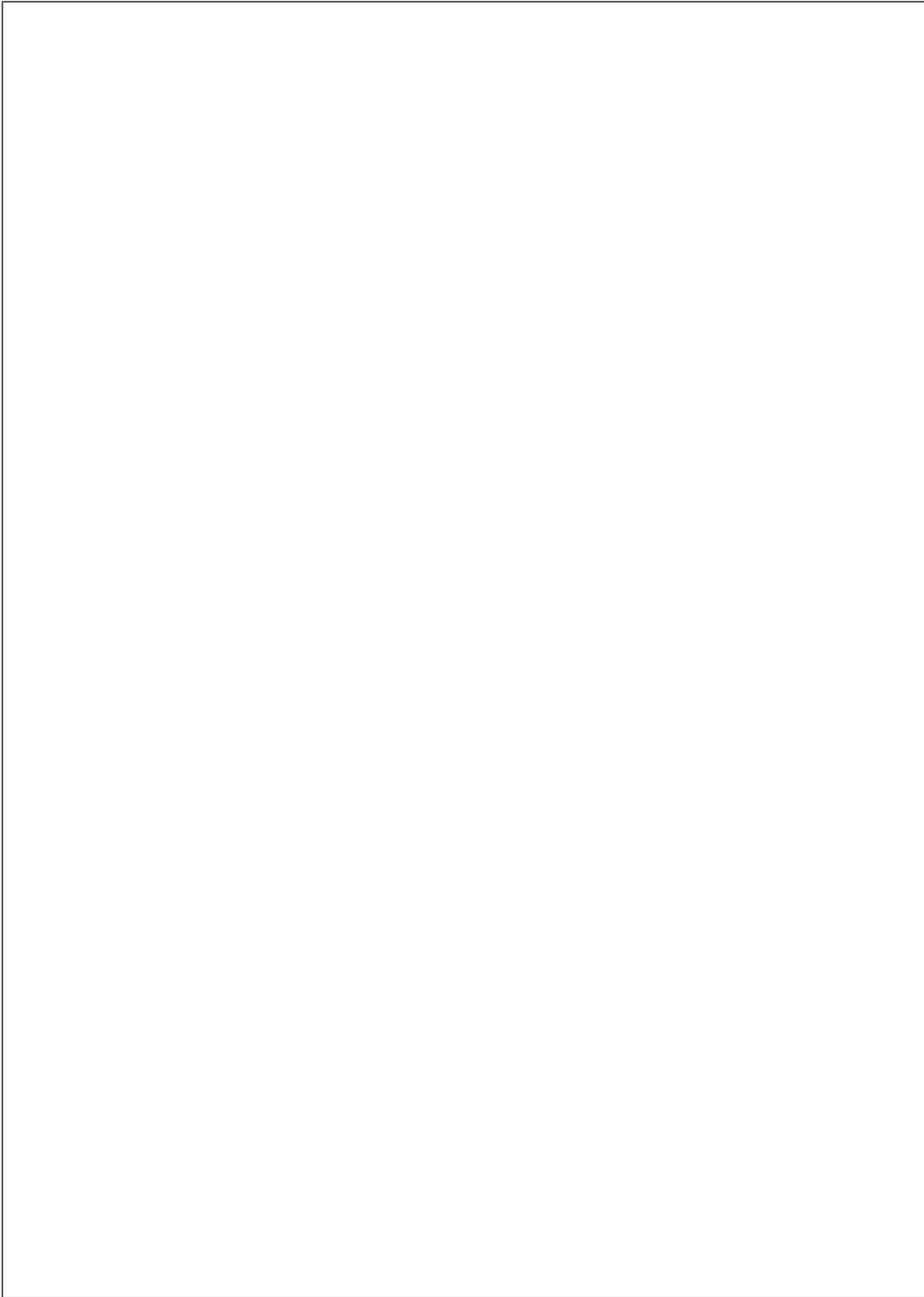
AC Electrical Characteristics

Symbol	Parameter	V _{CC} (V) (Note 4)	54AC		Units
			T _A = −55°C to +125°C C _L = 50 pF		
			Min	Max	
t _{PLH}	Propagation Delay	3.3	1.0	12.5	ns
		5.0	1.0	9.0	
t _{PHL}	Propagation Delay	3.3	1.0	12.5	ns
		5.0	1.0	9.0	

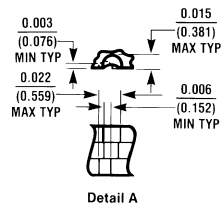
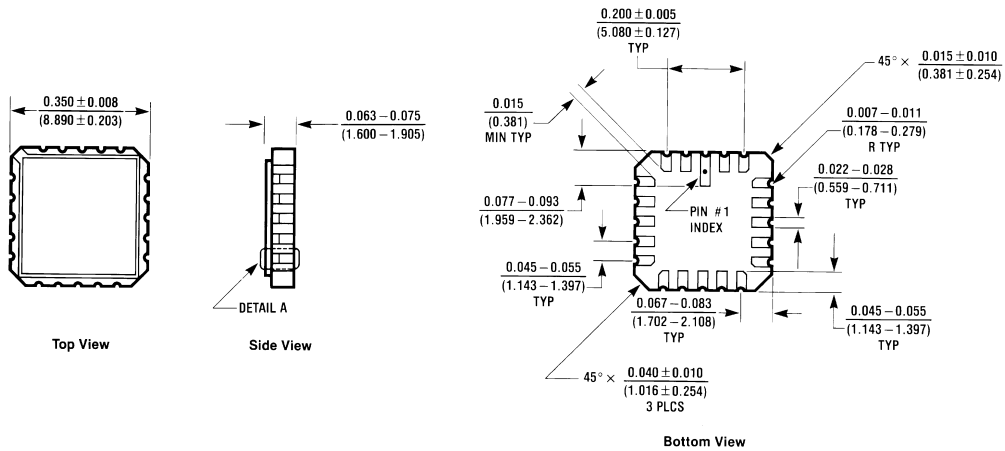
Note 4: Voltage Range 3.3 is 3.3V ± 0.3V
Voltage Range 5.0 is 5.0V ± 0.5V

Capacitance

Symbol	Parameter	Typ	Units	Conditions
C _{IN}	Input Capacitance	4.5	pF	V _{CC} = OPEN
C _{PD}	Power Dissipation Capacitance	20.0	pF	V _{CC} = 5.0V

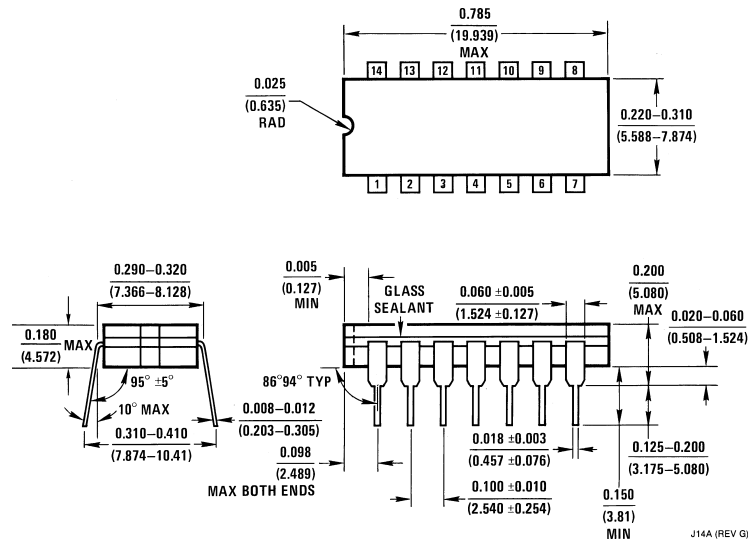


Physical Dimensions inches (millimeters) unless otherwise noted

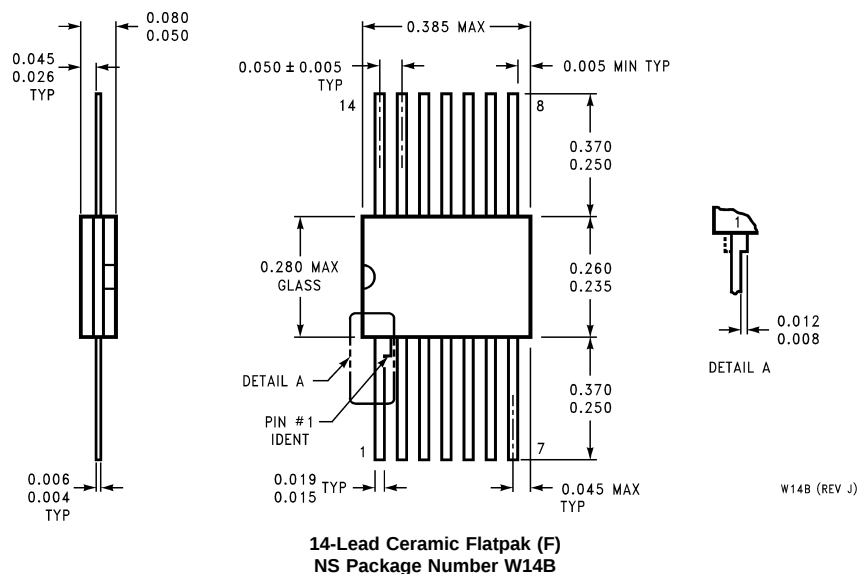


E20A (REV D)

20-Terminal Ceramic Leadless Chip Carrier (L) NS Package Number E20A



14-Lead Ceramic Dual-In-Line Package (D) NS Package Number J14A

Physical Dimensions inches (millimeters) unless otherwise noted (Continued)**LIFE SUPPORT POLICY**

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